

The New eFlash XS

Simplicity is the ultimate sophistication!

The speed of scientific and technological advancement is influenced by many important factors among which is the availability of techniques needed by scientists and engineers to further their understanding of a material's nature and properties. Scanning Electron Microscopy (SEM) complemented by Energy Dispersive Spectroscopy (EDS) and Electron BackScatter Diffraction (EBSD) is a very powerful combination of techniques enabling qualitative and quantitative characterization of materials. While the SEM and EDS techniques are being used widely and effectively worldwide, the EBSD technique is lagging EDS utilization by at least a factor of 10. The major factor responsible for this situation is affordability and the investment risks connected to it. In other words, due to high costs for combined EDS & EBSD, the two techniques have been mainly delivered so far with high-end SEMs thus dramatically limiting the number of labs able to add these capabilities to their analytical portfolio.

To change the status-quo and significantly increase the number of labs able to acquire an integrated EDS & EBSD system, Bruker Nano has developed e-Flash XS, a unique EBSD detector dedicated to the affordable part of the SEM market. The eFlash XS EBSD detector was purposely designed to be installed on low footprint SEMs, e.g. tabletop SEMs and standard SEMs with small chambers.



Our EBSD expertise has been tapped for developing the most reliable and most affordable EBSD detector ever, while providing excellent performance. Designed for maximum reliability, ease of use and pattern quality, e-Flash XS is powered by a binning capable CMOS camera, an innovative optical system for maximum light transmission and a high-performance user-replaceable phosphor screen. Its USB3.0 computer connection (power & data) makes eFlash XS a truly plug-n-play instrument. When not in use, the in-SEM portion of the EBSD detector slides off for external storage, to eliminate any risk of the SEM stage colliding with the detector.